

MS30N06X

N-CHANNEL ENHANCEMENT MODE POWER MOSFET

BVDSS	30V
RDS(ON)	4.5mΩ
ID	40A

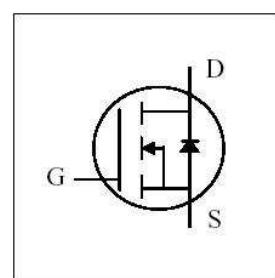
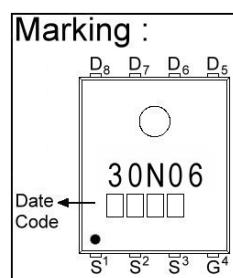
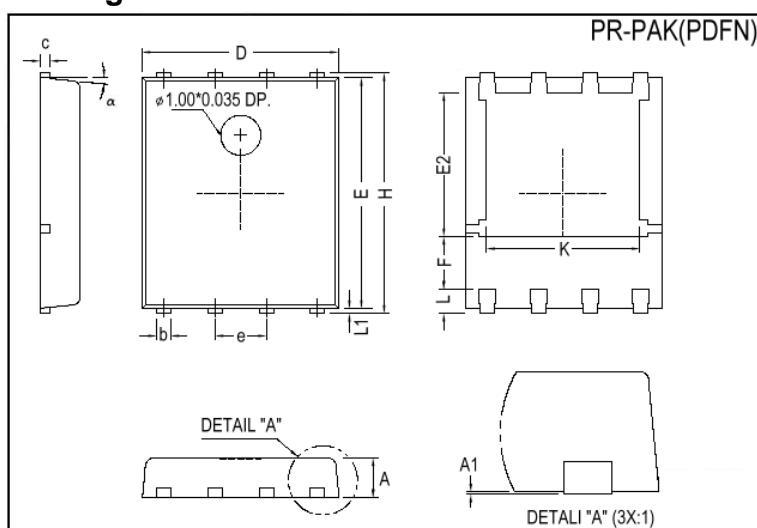
Description

The MS30N06X uses advanced Trench technology and designs to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications. The GPR30N06 meet the RoHS and Green Product requirement, 100% EAS and R_g guaranteed with full function reliability approved.

Features

- Low On-Resistance
 - Low Input Capacitance
 - Green Device Available
 - Low Miller Charge
 - 100% EAS and Rg Guaranteed

Package Dimensions



REF.	Millimeter			REF.	Millimeter		
	Min.	Nom.	Max.		Min.	Nom.	Max.
A	0.85	1.00	1.15	E	5.70	-	5.90
A1	0.00	-	0.10	e	-	1.27	-
b	0.30	-	0.51	H	5.90	-	6.20
c	0.20	-	0.30	L	-	0.60	-
D	4.80	-	5.00	L1	0.06	-	0.20
F	1.10REF.			α	0°	-	12°
E2	3.50REF			K	3.70	3.90	4.10

Absolute Maximum Ratings

Absolute Maximum Ratings			
Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current	I _D @ T _C =25°C	40	A
	I _D @ T _C =70°C	40	A
Pulsed Drain Current ¹	I _{DM}	100	A
Continuous Drain Current	I _D @ T _A =25°C	31	A
	I _D @ T _A =70°C	25	A
Total Power Dissipation	P _D @ T _C =25°C	36	W
	P _D @ T _A =25°C	4.2	W
Single Pulse Avalanche Energy, L=0.1mH	E _{AS}	72	mJ
Single Pulse Avalanche Current, L=0.1mH	I _{AS}	38	A
Operating Junction and Storage Temperature Range	T _J T _{STG}	-55 ~ +150	°C

Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient ²	R _{θJA}	Steady State	30	°C/W
Thermal Resistance Junction-case ²	R _{θJC}	Steady State	3.5	°C/W

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Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=250\mu\text{A}$
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	1.15	-	2.2	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
Forward Transconductance ¹	g_{fs}	-	82	-	S	$\text{V}_{\text{DS}}=15\text{V}, \text{I}_D=19\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	I_{DSS}	-	-	1	μA	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0$
Static Drain-Source On-Resistance ¹	$\text{R}_{\text{DS}(\text{ON})}$	-	3.3	4.5	$\text{m}\Omega$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=19\text{A}$
		-	4.6	5.6		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=16\text{A}$
Total Gate Charge ¹	Q_g	-	12	-	nC	$\text{I}_D=19\text{A}$ $\text{V}_{\text{DS}}=15\text{V}$ $\text{V}_{\text{GS}}=4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	6	-		
Gate-Drain ("Miller") Change	Q_{gd}	-	5	-		
Turn-on Delay Time ¹	$\text{T}_{\text{d}(\text{on})}$	-	24	-	ns	$\text{V}_{\text{DS}}=15\text{V}$ $\text{I}_D=10\text{A}$ $\text{V}_{\text{GS}}=4.5\text{V}$ $\text{R}_G=1.0\Omega$ $\text{R}_L=1.5\Omega$
Rise Time	T_r	-	21	-		
Turn-off Delay Time	$\text{T}_{\text{d}(\text{off})}$	-	25	-		
Fall Time	T_f	-	17	-		
Input Capacitance	C_{iss}	-	1750	-	pF	$\text{V}_{\text{GS}}=0\text{V}$ $\text{V}_{\text{DS}}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	360	-		
Reverse Transfer Capacitance	C_{rss}	-	150	-		
Gate Resistance	R_g	-	3.2	5.0	Ω	$f=1.0\text{MHz}$

Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy ³	EAS	48	-	-	mJ	$\text{V}_{\text{DD}}=20\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=31\text{A}$

Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage ¹	V_{SD}	-	0.8	1.2	V	$\text{I}_S=10\text{A}, \text{V}_{\text{GS}}=0\text{V}$
Continuous Source Current ¹	I_S	-	-	40	A	---
Reverse Recovery Time	t_{rr}	-	25	-	ns	$\text{I}_F=10\text{A}, \text{dI}/\text{dt}=100\text{A}/\mu\text{s},$ $\text{T}_J=25^\circ\text{C}$
Reverse Recovery Charge	Q_{rr}	-	17	-	nC	

Notes: 1. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

2. R_{eJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{eJC} is guaranteed by design while R_{eCA} is determined by the user's board design. R_{eJA} shown below for single device operation on FR-4 in still air.
3. The Min. value is 100% EAS tested guarantee.

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Typical Characteristics

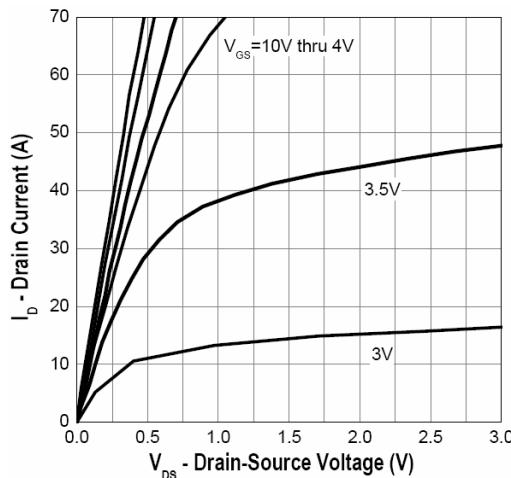


Fig.1 Typical Output Characteristics

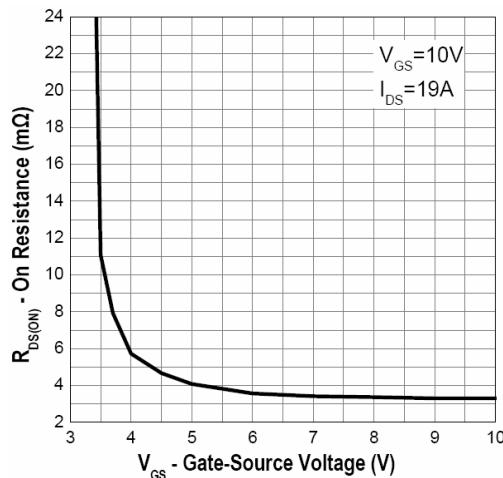


Fig.2 On-Resistance vs. G-S Voltage

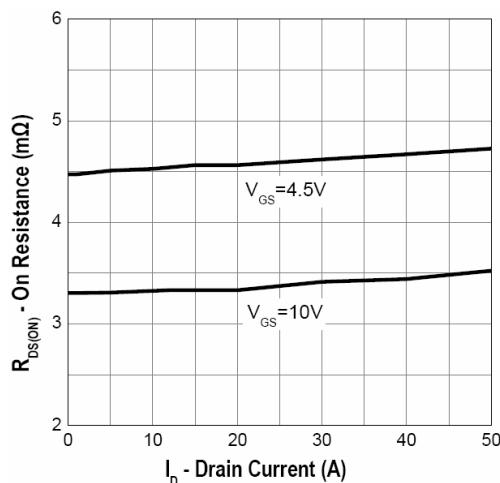


Fig.3 On-Resistance vs. Drain Current

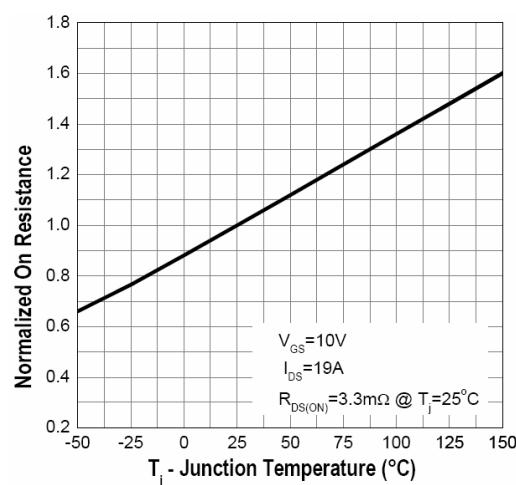


Fig.4 Normalized $R_{DS(ON)}$ vs. T_j

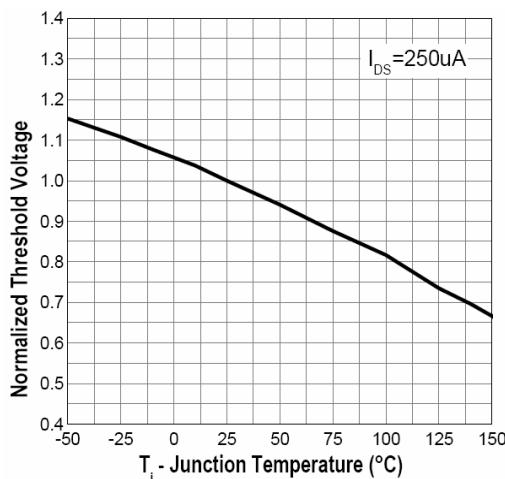


Fig.5 Normalized $V_{GS(th)}$ vs. T_j

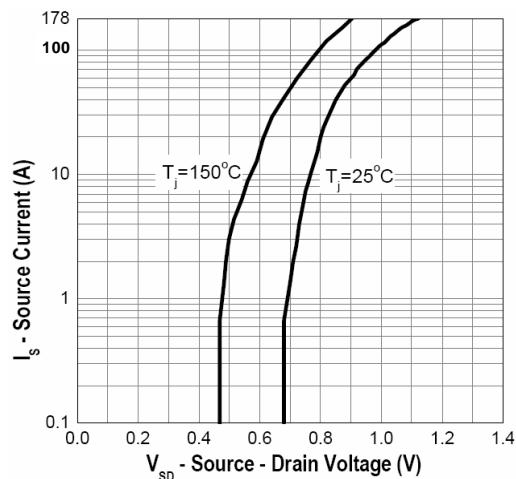


Fig.6 Forward Characteristics of Reverse

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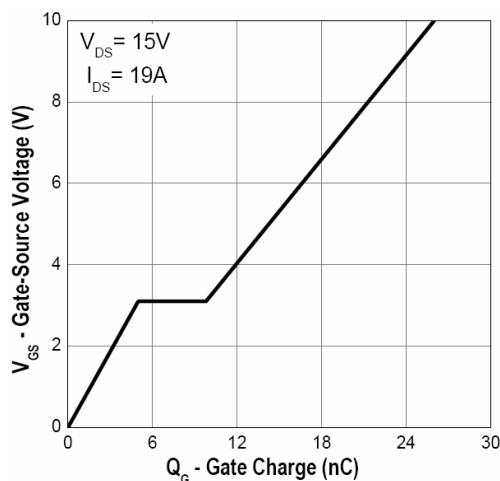


Fig.7 Gate Charge Characteristics

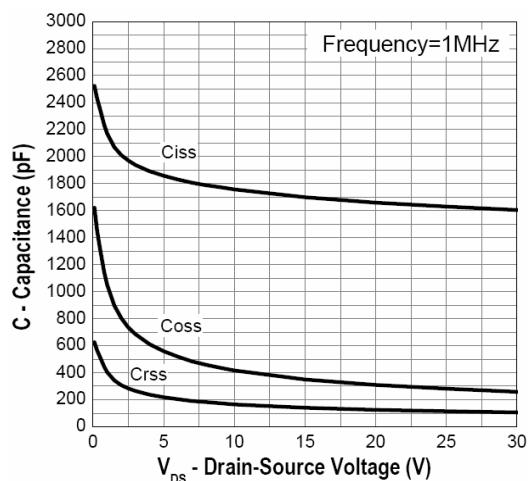


Fig.8 Capacitance Characteristics

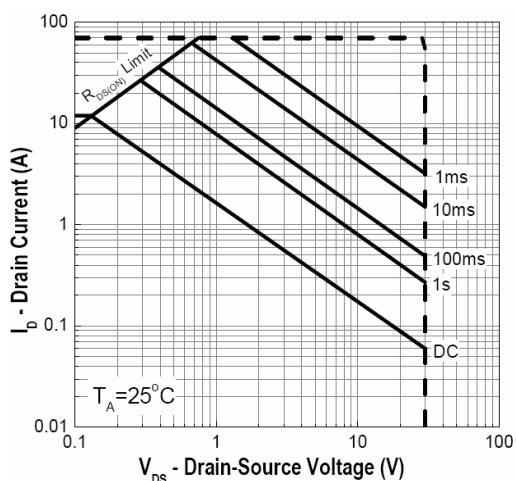


Fig.9 Safe Operating Area

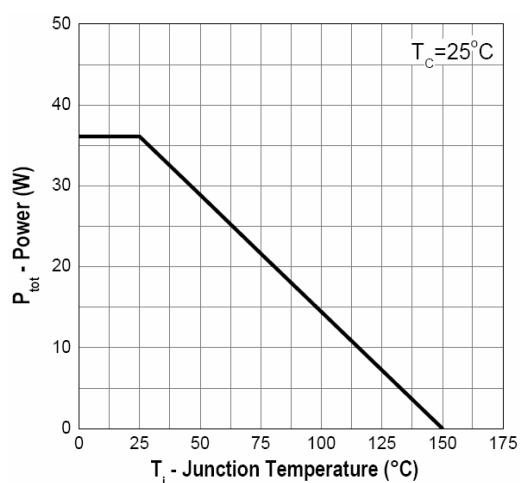


Fig.10 Power Dissipation

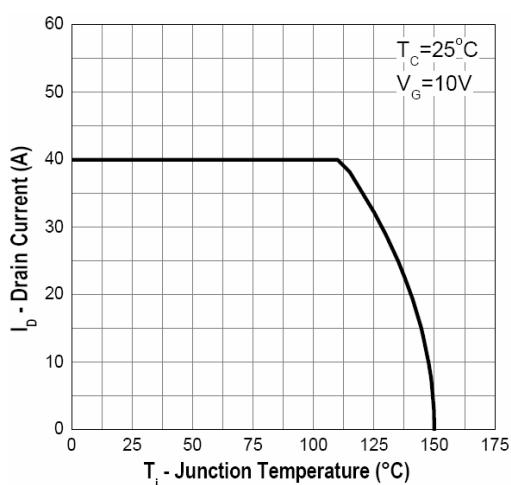


Fig.11 Drain Current vs. T_j

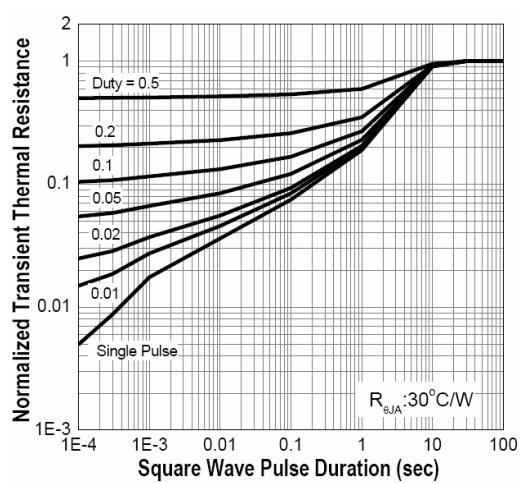


Fig.12 Transient Thermal Impedance